

Title (en)

TEST CIRCUIT CONFIGURATION AND METHOD FOR TESTING A LARGE NUMBER OF TRANSISTORS

Title (de)

TEST-SCHALTUNGSANORDNUNG UND VERFAHREN ZUM TESTEN EINER VIELZAHL VON TRANSISTOREN

Title (fr)

AGENCEMENT DE CIRCUITS DE TEST ET PROCEDE PERMETTANT DE TESTER PLUSIEURS TRANSISTORS

Publication

**EP 1269204 A2 20030102 (DE)**

Application

**EP 01915081 A 20010305**

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Abstract (en)

[origin: WO0167601A2] The invention relates to a test circuit configuration. Every gate terminal of a transistor to be tested is coupled to a gate voltage source in such a manner that the gate voltage can be measured and adjusted individually on every gate terminal. The source terminal of every transistor to be tested can be coupled to the source voltage source in such a manner that the source voltage can be measured and adjusted individually on every source terminal.

IPC 1-7

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IPC 8 full level

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Citation (search report)

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**DE 0100835 W 20010305**; EP 01915081 A 20010305; KR 20027011777 A 20020909; US 22044903 A 20030113